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| FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S) INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | ATTY. DOCKET NO. 02EK-105598 | SERIAL NO. 10/808,665 |
| | APPLICANT: Lidu Huang, et al. | |
| | FILING DATE: March 24, 2004 | GROUP ART UNIT: 2877 |



REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

| EXAM'R INITIAL | | DOCUMENT NUMBER | DATE | NAME | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|--------------------|------------|-------------|-------|----------|-------------------------------|
| KG | A1 | 6,504,966 | 01/07/2003 | Kato et al. | 385 | 16 | |
| | A2 | | | | | | |
| | A3 | | | | | | |
| | A4 | | | | | | |

FOREIGN PATENT DOCUMENTS

| EXAM'R INITIAL | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | Subclass | TRANSLAT'N | |
|-------------------|---|--------------------|------|---------|-------|----------|------------|----|
| | | | | | | | yes | no |
| | B | | | | | | | |
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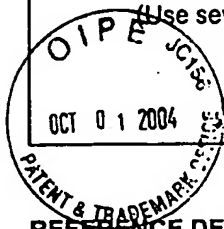
OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

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|----|----|--|--|--|--|--|--|
| KG | C1 | "Silica Integrated Optical Circuits", edited by H. M. Presby, Section 2 "Fabrication", SPIE Milestone Series, vol. MS 125, pp. 43-149, 1996 | | | | | |
| KG | C2 | T. Fukano and I. Yamoguchi, "Simultaneous measurement of thickness and refractive indices of multilayers by a low-coherence confocal interference microscope", Opt. Lett., vol. 21, pp. 1942-1944, 1996 | | | | | |
| KG | C3 | G. J. Veldhuis, L.E. W. van Veen and P. V. Lambeck, "Integrated optical refractometer based on waveguide bend loss", IEEE J. Lightwave Technol., vl. 17, pp. 857-864, 1999 | | | | | |
| KG | C4 | D. C. Yin and Y. Inatomi, "Measurement of refractive index of GaP crystal over a large temperature range using interferometry", Cryst. Res. Technol., vol. 35, pp. 221-228, 2000 | | | | | |
| KG | C5 | T. Dennis, E. M. Gill and S. L. Gilbert, "Interferometric measurement of refractive-index change in photosensitive glass", Appl. Optics, vol. 40, pp. 1663-1667, 2001 | | | | | |
| KG | C6 | O. M. Efimov, L. B. Glebov and H. P. Andre, "Measurement of the induced refractive index in a photothermorefractive glass by a liquid-cell shearing interferometer", Appl. Optics, vol. 41, pp.1864-1870, 2002 | | | | | |

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| EXAMINER /Kara Geisel/ (12/26/2006) | DATE CONSIDERED |
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant(s).

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|-------------------|---|--------------------|------|------|-------|----------|-------------------------------|
| | A | | | | | | |
| | A | | | | | | |
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FOREIGN PATENT DOCUMENTS

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|-------------------|---|--------------------|------|---------|-------|----------|------------|----|
| | | | | | | | yes | no |
| | B | | | | | | | |
| | B | | | | | | | |

OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

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|----|-----|--|
| KG | C7 | A. L. Glebov, L. Huang, S. Aoki, M. G. Lee and K. Yokochi, "Two dimensional microlens arrays in silica-on-silicon planar lightwave circuit technology", Journal of Microlithography, Microfabrication, & Microsystems, vol 2, no. 4, pp. 309-318, 2003 |
| KG | C8 | Meticon Corp., "Model 2010 Prism Coupler Application Notes Measuring Index Anisotropy of Free-Standing Polymer Films," www.meticon.com/appli6.htm , 6/29/2004 |
| KG | C9 | Brother Gregory Investigates, "Measuring Refractive Index," www.brooklyn.cuny.edu/bc/ahp/CellBio/RefIndex/RI.Main.html , 6/30/2004 |
| | C10 | |
| | C11 | |
| | C12 | |

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